

CRYSTAL CLOCK OSCILLATORS

Data Sheet 0631B

Rev. A

HF/UHF SMD TCVCXO SG-XA3XXXX Series

Description

The **SG-XA3XXXX Series** of SMD temperature compensated, voltage controlled crystal oscillators (TCVCXO) provides High and Ultra High Frequency with excellent temperature stability, extremely low phase noise and jitter with variety of different output types in a small surface mount FR4 based package.

Applications and Features

- Ultra High Frequency - up to 1GHz
- Small, Low Profile SMD Package
- Very Low Phase Jitter and Phase Noise
- Excellent Frequency Stability
- CMOS, Sine-wave, Differential PECL or LVDS outputs available
- Stratum 3 available

Creating a Part Number			
Package Code		SG - X A3 X X X - FREQ	Temp Frequency Stability, ppm
SG 7 pad 1.0"x0.87" SMD			1 ±1.0
			2 ±2.5
			3 ±0.28
Input Voltage			
0 5.0V±5%			
A 3.3V±5%			
TCXO/TCVCXO Option			Temperature Range, °C
T No V. Control			B 0 to 70
V With V Control			C -20 to 70
			D -40 to 85
			E -10 to 60
			9 Customer specific
Output Type			
C CMOS			
P PECL			
S Sine-wave			
L LVDS			

NEL

**FREQUENCY
CONTROLS, INC.**

357 Beloit Street, P.O. Box 457, Burlington, WI 53105-0457 U.S.A. Phone 262/763-3591 FAX 262/763-2881
Email: nelsales@nelfc.com www.nelfc.com

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SG-XA3XXXX Series Continued
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Absolute Maximum Ratings

Parameter	Sym	Condition	Min	Typ	Max	Unit	Note
Input Break Down Voltage	V _{cc}		-0.5		5.5	V	
Storage Temperature	T _s		-40		105	°C	
Control Voltage	V _c		-1		9	V	

Electrical Parameters

Parameter	Sym	Conditions	MIN	TYP	MAX	Unit	Note
Frequency Range	F	CMOS Sine-wave PECL, LVDS	30 30 30		200 1,000 1,000	MHz	
Input Voltage	V _{cc}	Code 0 Code A	4.75 3.135	5.0 3.3	5.25 3.465	V	
Input current	I _{cc}	CMOS, Sine PECL, Sine, LVDS			30 100	mA	@100MHz, 3.3V @622MHz, 3.3V
Frequency Stability	ΔF/F	Overall, available			±4.6		20 years
Frequency Stability	ΔF/F	vs Temperature vs V _{cc} Aging		±0.5 ±0.1 ±1 ±3.5	±1	ppm ppm/V ppm/year ppm	See Chart First Year 10 years
Calibration	ΔF/F	As shipped, 25°C		±0.5	±1	ppm	
Load		CMOS Sinewave PECL LVDS	15pf/10KOhmOhm Internally AC-coupled 50 Ohm 50 Ohm to V _{cc} -2V or Thevenin equivalent 100 Ohm between the outputs, receiving end				
Duty Cycle		At 50 %	45/55	50/50	55/45	%	CMOS, PECL, LVDS
Rise/Fall Time	Tr/Tf	20 to 80%		3 0.35		ns	CMOS PECL, LVDS
Logic "1" level	V _{oh}	CMOS	0.9V _{cc}			V	
Logic "0" level	V _{ol}	CMOS			0.1V _{cc}	V	
Logic "1" level	V _{oh}	PECL	V _{cc} -0.96		V _{cc} -0.81	V	100K available
Logic "0" level	V _{ol}	PECL	V _{cc} -1.85		V _{cc} -1.65	V	100K available
Output Levels LVDS	V _{od}	Differential amplitude	247	330	454	mV	
		Amplitude error			50	mV	
	V _{of}	Offset Voltage	1.125	1.25	1.375	V	
		Offset Voltage error			50	mV	
Output power	P	Sinewave Into 50 Ohm	4	37		dBm	3.3V 5.0V
Start up Time	T _s			2	10	ms	
Phase jitter		1 sigma		0.4 0.2	1 0.4	ps	100Hz to 20MHz 12kHz to 20MHz
Sub-harmonics		PECL, LVDS, Sine CMOS, Sine		-45	-40 none	dBc	F>250MHz F<250MHz
Spurious					-60	dBc	
Harmonics		Sine-wave		-30	-25	dBc	
SSB Phase Noise		@10 Hz @100 Hz @1 KHz @10KHz @100KHz		-80 -110 -140 -155 -160		dBc/Hz	@ 100 MHz
SSB Phase Noise		@10 Hz @100 Hz @1 KHz @10KHz @100KHz		-60/-60 -90/-90 -120/-120 -140/-145 -145/-150		dBc/Hz	@ 622 Mhz; PECL, LVDS/Sine
Input Impedance			> 10 K Ohm				
Control Voltage	V _c		0		3.3	V	
Modulation Bandwidth	MB		100Hz				Contact Factory for wider MB
Deviation		V _c =0V to 3.3V, 25°C	±5	±7		ppm	



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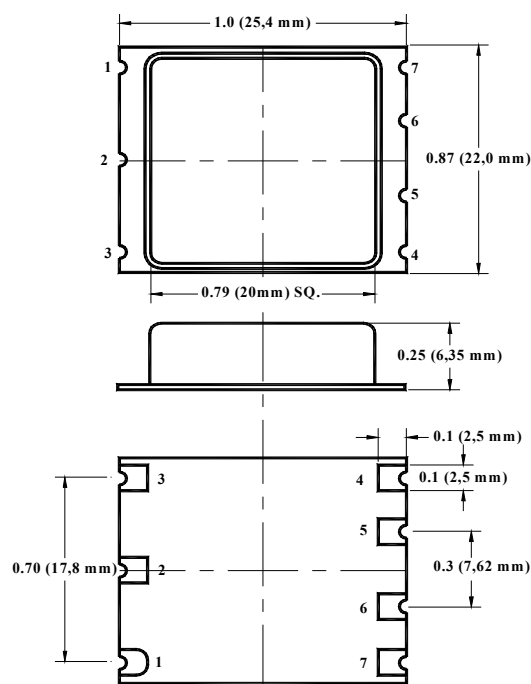
SG-XA3XXXX Series Continued

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Electrical Connection

Pin	Connection
1	Voltage Control
2	NC
3	V _{CC}
4	Output, CMOS or Sine
5	Output, PECL/LVDS
6	Comp. Output, PECL/LVDS
7	Gnd

Note: For frequency stability over temperature ± 1 ppm and tighter, the package height may be 10mm or 12.5mm.



Environmental and Mechanical Characteristics

Operating temp. range	0°C to 70°C, -40°C to 85°C, see chart page 1
Mechanical Shock	Per MIL-STD-202, Method 213, Cond. E
Thermal Shock	Per MIL-STD-883, Method 1011, Cond. A
Vibration	Per MIL-STD-883, Method 2007, Cond. A
Hermetic Seal	Leak rate less than 1×10^{-8} atm.cc/s of helium (crystal only)
Soldering conditions	See MAX reflow profile below

Maximum Reflow Profile

